IFW 2812

03500.017731.



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| In re Ap | oplication of: |) | · |
|-----------------------------|-----------------------|---|------------------------------|
| | · | : | Examiner: Michael Lebentritt |
| HIDEYA KUMOMI ET AL. | |) | |
| | uq | : | Group Art Unit: 2812 |
| Application No.: 10/533,091 | |) | |
| | • | : | |
| Filed: April 28, 2005 | |) | |
| | | : | |
| For: | PRODUCING METHOD FOR | | |
| | CRYSTALLINE THIN FILM |) | August 29, 2006 |

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed foreign documents and articles are also enclosed.

The concise explanation of relevance for the non-English document is found in the specification where cited, and in an attached abstract.

CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that an initialed copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

Peter Sakon

Attorney for Applicants Registration No.: 24,947

FITZPATRICK, CELLA, HARPER & SCINTO 30 Rockefeller Plaza
New York, New York 10112-3800
Facsimile: (212) 218-2200

NY_MAIN 588957v1

| | | | VSE / | | | | | | |
|---|--|---|-----------------|---|-------|------------|---------------------------------------|--|--|
| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OF FICE (1) 3 0 2006 | | | | ATTY DOCKET NO. APPLICATION NO. 10/533,091 | | |)91 | | |
| | PATEN | NT AND TRADEMARK OFFIC | | APPLICANT | | | | | |
| LIST | OF REF | ERENCES CITED BY APP e several sheets if necessary | SANT(S) | HIDEYA KUMOMI, ET AL. | | | | | |
| | (USe | several sneets ii necessary) | TRADE | FILING DATE | | GROUP | | | |
| | | | | April 28, 2005 | | 2812 | | | |
| | U.S. PATENT DOCUMENTS | | | | | | | | |
| *EXAMINER INITIAL | <u> </u> | DOCUMENT NUMBER | DATE | NAME | CLAS | s subclass | FILING DATE IF APPROPRIATE | | |
| | | 5,130,103 | 07/14/92 | Yamagata et al. | 428 | 209 | | | |
| | | 5,207,863 | 05/04/93 | Kumomi | 156 | 603 | | | |
| | | 5,290,712 | 03/01/94 | Sato, et al. | 437 | 24 | | | |
| | | 5,723,348 | 03/03/98 | Kumomi et al. | 437 | 23 | , | | |
| | | | | | | | | | |
| | <u> </u> | | FO | REIGN PATENT DOCUMENTS | | | | | |
| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT | | |
| | JP | 8-8197 | 01/12/96 | Japan | | | Abstract | | |
| | | | | | | | g f | | |
| | | | | | | | | | |
| | | | | | | | | | |
| | | | | | | | | | |
| | 1 | C | THER DOCUMENT(S | i) (Including Author, Title, Date, Pertinent Pages, E | etc.) | | | | |
| | | | | | | Approach (| for Thin | | |
| <u></u> | Kumomi, et al. "Selective Nucleation-based Epitaxy (SENTAXY): A novel Approach for Thin Film Formation"; JPN J. Appl. Phys., Vol. 36 pp 1383-1388 (1997). | | | | | | | | |
| | Kumomi, et al. "Fundamentals for the Formation and Structure Control of Thin Films: | | | | | | | | |
| | | Nucleation, Growth, Solid-state Transformations"; Handbook of Thin Film Materials, Vol. 7, Ch. 6, pp 319-373 (2002). | | | | | | | |
| | | Hatano, et al. "Excimer Laser-induced Temperature Field in Melting and Resolidification of Silicon Thin Films"; J. Appl. Phys., Vol. 87, No. 1, pp. 36-43 (2000). | | | | | | | |
| | Van der Wilt, et al. "Formation of Location-controlled Crystalline Islands Using Substrate- embedded Seeds in Excimer-laser Crystallization of Silicon Films"; Appl. Phys. Lett, Vol. 79, | | | | | | | | |
| | | No. 12, pp 1819- | 1821 (2001) | | | | | | |
| EXAMINER | | | | DATE CONSIDERED | | | | | |

| Sheet | 1 | of | 1 |
|-------|---|----|---|

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.